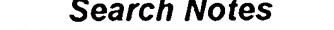


Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/724,768	KIM ET AL.
	Examiner	Art Unit
	Filip Zec	3744

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
62	408	6/12/2005	FZ
62	404-407	6/12/2005	FZ
62	187	6/12/2005	FZ